

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO.: CHUDоба, T. 1 PCT		SERIAL NO.: 10/532630	
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Thomas Chudoba et al.			
				FILING DATE: Sept. 7 2005 GROUP: 2855			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JD	AA	5,051,594	09/1991	Fumihiko et al. Tsuda et al.			
JD	AB	4,157,818	06/1979	Key			
JD	AC	3,201,980	08/1965	Webb			
JD	AD	5,343,748	09/1994	Keasey, et al. Mozgowiec et al.			
JD	AE	2,573,286	10/1951	Baker, et al.			
	AF						
	AG						
	AH						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
JD	AL	WO 02 16907	02/2002	PCT			
JD	AM	WO 99 46576	09/1999	PCT			
	AN						
	AO						
	AP						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
JD	AQ		"Microscratch and Load Relaxation Tests for Ultra-Thin Films" - Wu T. W. Journal of Materials Research, New York, NY, U.S., Vol. 6, no. 2, pages 407-426 February 1991				
JD	AR		International Search Report				
	AS						
EXAMINER /Jonathan Dunlap/				DATE CONSIDERED 03/02/2007			
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1966-2005 Our 39th Year

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.:

CHUDоба, et al PCT

SERIAL NO.:

10/532,630

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT:

Thomas Chudoba et al

FILING DATE:

Sept. 7, 2005

GROUP:

2855

U.S. PATENT DOCUMENTS

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JD	AR	International Search Report					
	AS						

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